

<b>Notice of References Cited</b>	Application/Control No. <b>09/889,812</b>	Applicant(s)/Patent Under Reexam <b>Ronaghi</b>
	Examiner <b>Arun Chakrabarti</b>	Art Unit <b>1634</b>

**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>
A				
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**FOREIGN PATENT DOCUMENTS**

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P					
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R					
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T					

**NON-PATENT DOCUMENTS**

	<b>Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages</b>	
U		Chou, "Minimizing deletion mutagenesis artifact during taq DNA polymerase PCR by E.coli SSB", Nucleic Acids Research, (1992), Vol. 20, No. 6, page 4371.
V		Stratagene Catalog, "Gene Characterization kits", (1998), page 39.
W		
X		

\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>1</sup> Dates in MM-YYYY format are publication dates.

<sup>2</sup> Classifications may be U.S. or foreign.